

#### **Description**

The CPH3340-TL-E uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

## D S G

**SOT-23-3L** 

# G D D

P-Channel MOSFET

#### **General Features**

$$\begin{split} V_{DS} &= -20V \ I_D = -4.1A \\ R_{DS(ON)} &< 45 \text{m}\Omega @ V_{GS} = -4.5V \\ \text{ESD Rating: } 1500V \ \text{HBM} \end{split}$$

### **Application**

Battery protection

Load switch

Uninterruptible power supply

## **Package Marking and Ordering Information**

Product ID	Pack	Marking	Qty(PCS)
CPH3340-TL-E	SOT-23-3L	AFTV	3000

## Absolute Maximum Ratings (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Limit	Unit	
Drain-Source Voltage	-20	V	
Gate-Source Voltage	±10	V	
Drain Current-Continuous	-4.1	A	
Drain Current-Pulsed (Note 1)	-30	A	
Maximum Power Dissipation	1.4	W	
Operating Junction and Storage Temperature Range	-55 To 150	$^{\circ}$	
Thermal Resistance, Junction-to-Ambient (Note 2)	89.3	°C/W	
	Gate-Source Voltage  Drain Current-Continuous  Drain Current-Pulsed (Note 1)  Maximum Power Dissipation  Operating Junction and Storage Temperature Range	Gate-Source Voltage ±10  Drain Current-Continuous -4.1  Drain Current-Pulsed (Note 1) -30  Maximum Power Dissipation 1.4  Operating Junction and Storage Temperature Range -55 To 150	



## Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

Zero Gate Voltage Drain Current I <sub>DSS</sub>		V <sub>DS</sub> =-20V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±10V,V <sub>DS</sub> =0V	-	-	±10	μA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ , $I_{D}=-250\mu A$	-0.35	-0.55	-0.9	٧
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A	-	34	45	mΩ
Diam-Source On-State Resistance		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-4A	-	44	60	mΩ
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =-5V,I <sub>D</sub> =-4A	8	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C <sub>lss</sub>	\/ - 40\/\/ -0\/	-	950	-	PF
Output Capacitance	$C_{oss}$	$V_{DS}$ =-10V, $V_{GS}$ =0V, F=1.0MHz	-	165	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F-1.UIVITZ	-	120	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>		-	12		nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =-10V,R <sub>L</sub> =2. 5Ω $V_{GS}$ =-4.5V,R <sub>GEN</sub> =3Ω	-	10		nS
Turn-Off Delay Time	t <sub>d(off)</sub>		-	19		nS
Turn-Off Fall Time	t <sub>f</sub>		-	25		nS
Total Gate Charge	$Q_g$	\/ 40\/ L 44	-	12		nC
Gate-Source Charge	$Q_{gs}$	$V_{DS}$ =-10V, $I_{D}$ =-4A, $V_{GS}$ =-4.5V	-	1.4	-	nC
Gate-Drain Charge	$Q_{gd}$	V <sub>GS</sub> 4.5V	-	3.6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =-4A	-	-	-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-4	Α

#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width ≤  $300\mu$ s, Duty Cycle ≤ 2%.
- **4.** Guaranteed by design, not subject to production



## **Typical Electrical And Thermal Characteristics**

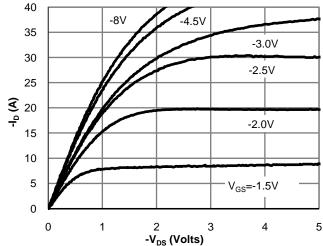


Fig 1: On-Region Characteristics (Note E)

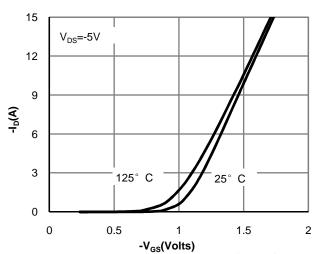


Figure 2: Transfer Characteristics (Note E)

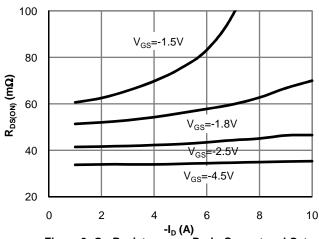


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

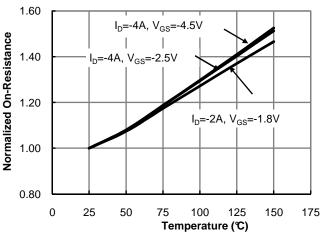


Figure 4: On-Resistance vs. Junction Temperature (Note E)

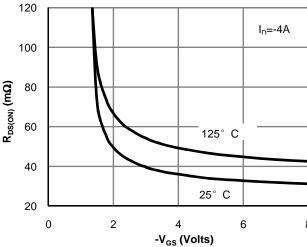


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

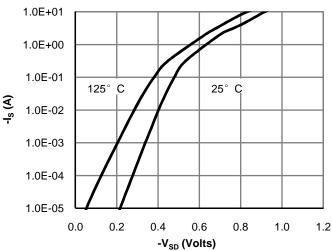
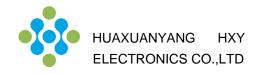
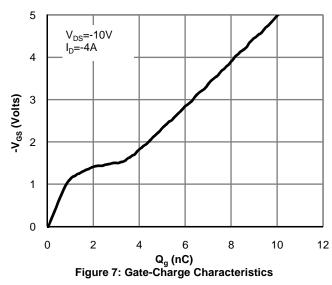
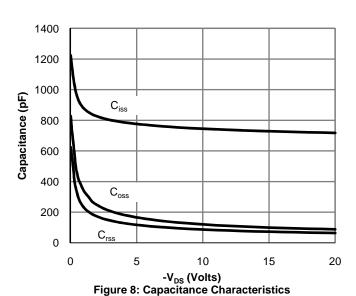
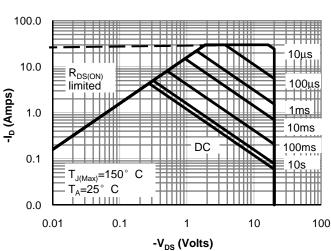


Figure 6: Body-Diode Characteristics (Note E)









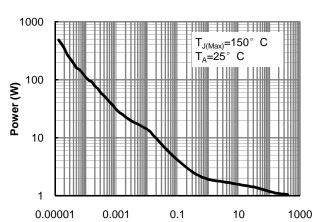


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Pulse Width (s)
Figure 10: Single Pulse Power Rating Junction-toAmbient (Note F)

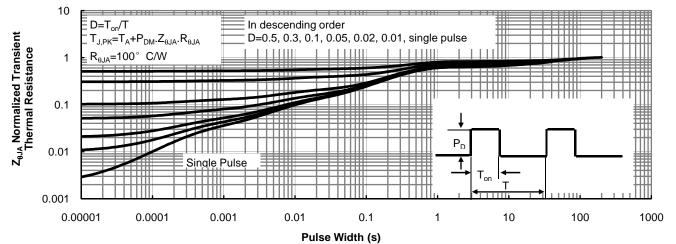
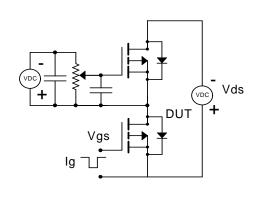
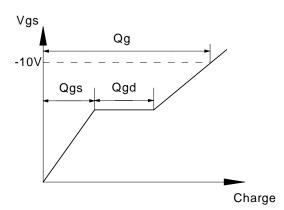


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

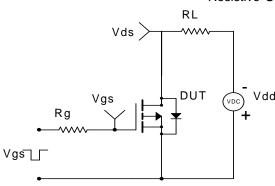


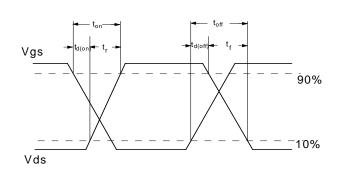
#### Gate Charge Test Circuit & Waveform



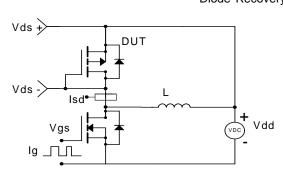


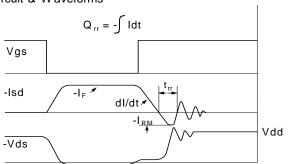
Resistive Switching Test Circuit & Waveforms





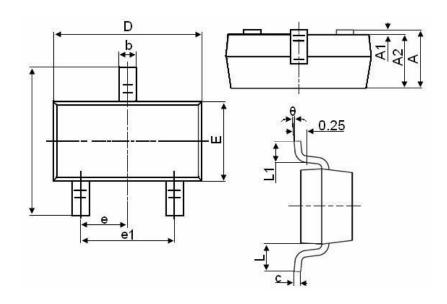
Diode Recovery Test Circuit & Waveforms







## **SOT-23-3L Package Information**



Symbol	Dimensions in Millimeters			
	MIN.	MAX.		
А	1.050	1.250		
A1	0.000	0.100		
A2	1.050	1.150		
b	0.300	0.500		
С	0.100	0.200		
D	2.800	3.000		
E	1.500	1.700		
E1	2.650	2.950		
е		0.950TYP		
e1	1.800	2.000		
L		0.550REF		
L1	0.300	0.600		
θ	0°	8°		



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